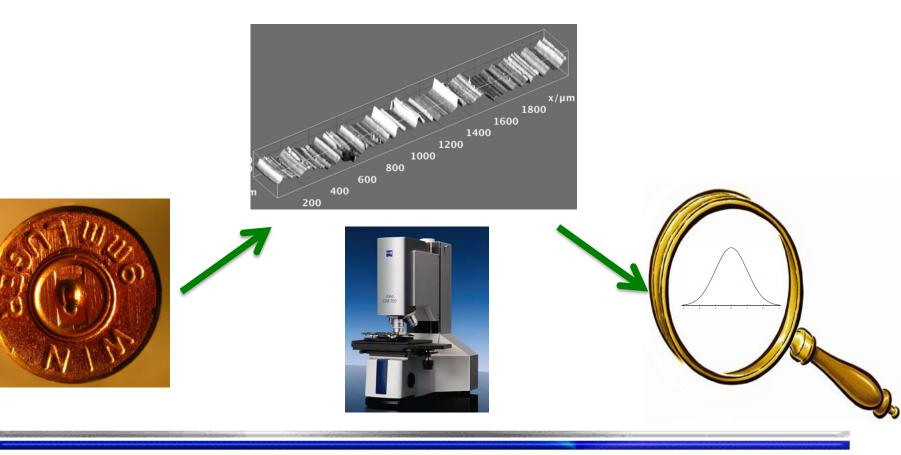
Computational Strategies for Toolmarks: Principal Component Analysis and Other Methods



Outline

- Introduction
- Details of Our Approach
 - Data acquisition
 - Methods of statistical discrimination
 - Error rate estimates
 - Measures of a association quality
 - Future directions

Background Information

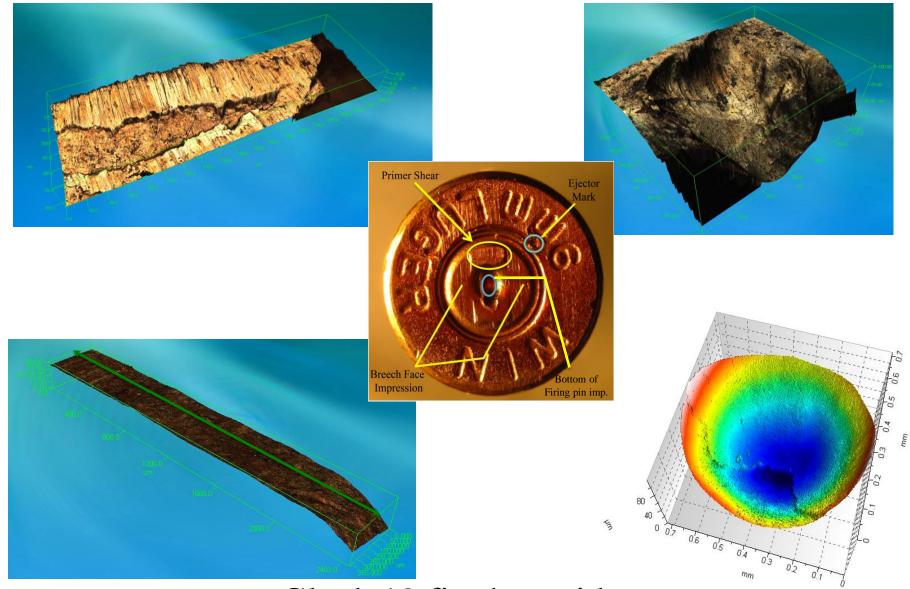
- <u>All impressions</u> made by tools and firearms can be represented as <u>numerical patterns</u>
 - Machine learning trains a computer to recognize patterns
 - Can give "...the quantitative difference between an identification and non-identification"^{Moran}
 - Can yield **identification error rate estimates**
 - May be even **confidence measures for I.D.s**.....

Data Acquisition

- Obtain striation/impression patterns from **3D confocal microscopy**
- Store files in ever expanding database
- Data files are available to practitioner and researcher community through web interface

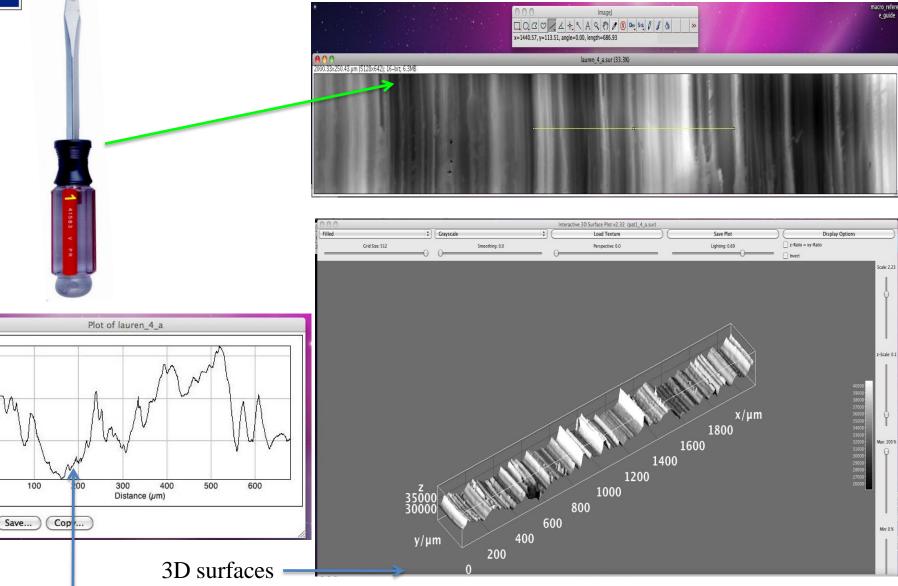


Glock Fired Cartridges



Glock 19 fired cartridge cases

Screwdriver Striation Patterns in Lead



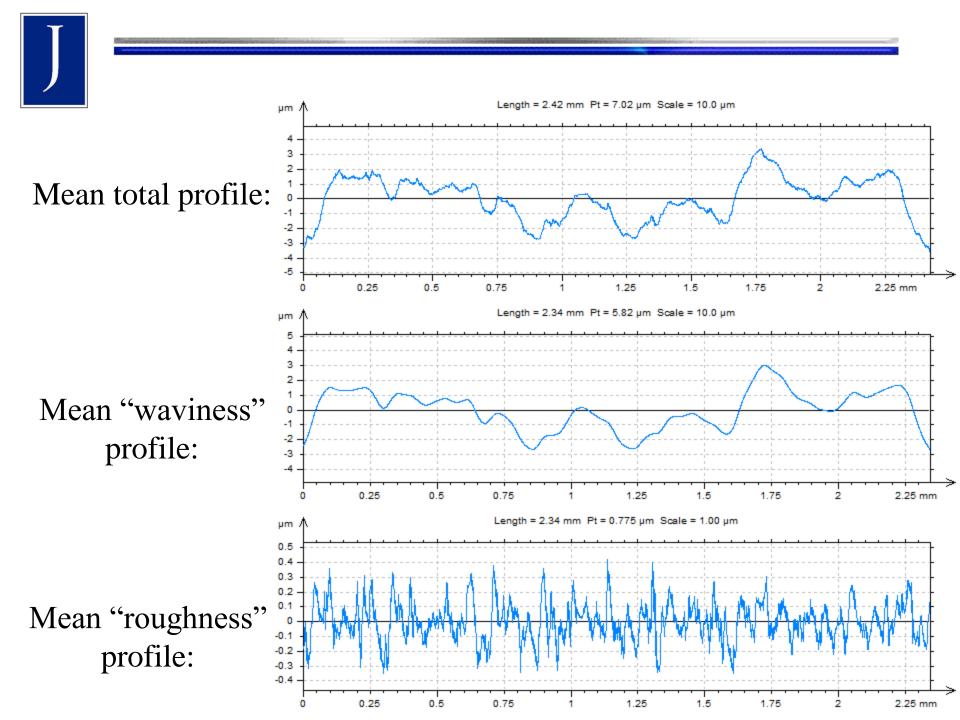
2D profiles (interactive)

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2 50

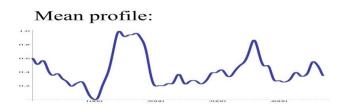
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List

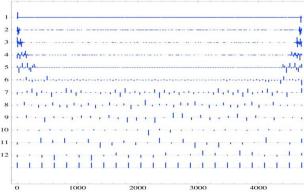


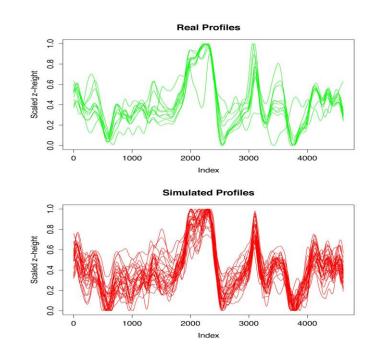
Profile Simulator

- We can simulate profiles as well
- Based on DWT MRA
 - May shed light on processed generating surfaces
 - Should be extendable to 2D striations/impressions...



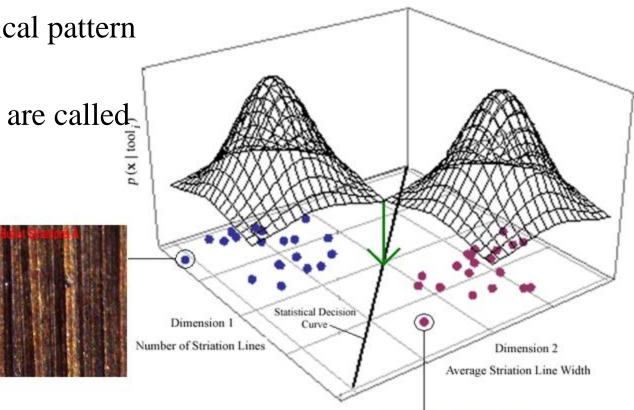
MRA (wavelet coefficients):





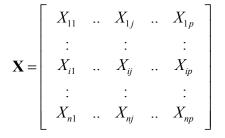
What Statistics Can Be Used?

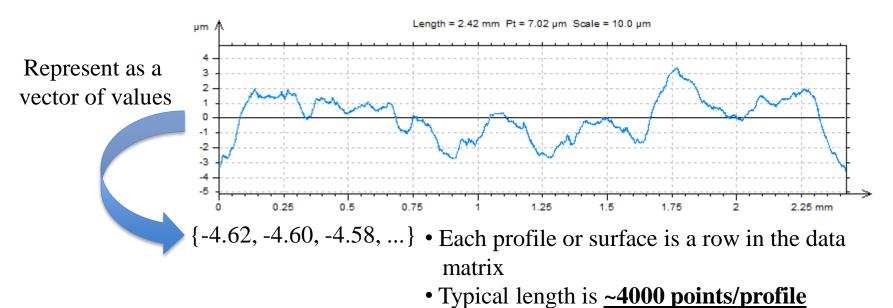
- Multivariate statistical pattern comparison!
- Modern algorithms are called machine learning
 - Idea is to measure features of the physical evidence that characterize it
- Train algorithm to recognize "major" differences between groups of features while taking into account natural variation and measurement error.



Setup for Multivariate Analysis

• Need a data matrix to do machine learning





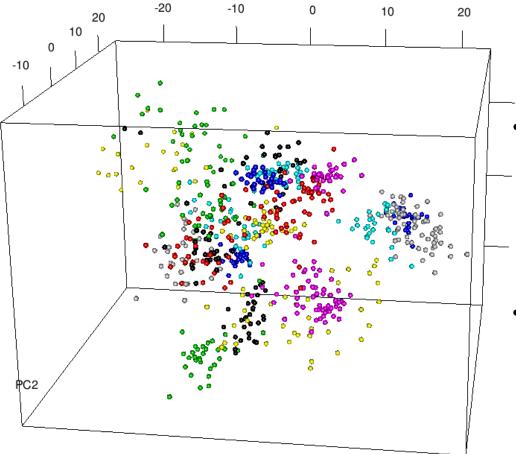
- PCA can:
 - Remove much of the redundancy
 - Make discrimination computations far more tractable
- HIGHLY REDUNDANT representation of surface data

• 2D surfaces are far longer



PC3

• 3D PCA 24 Glocks, 720 simulated and real primer shear profiles:



- How many PCs should we use to represent the data??
 - No unique answer

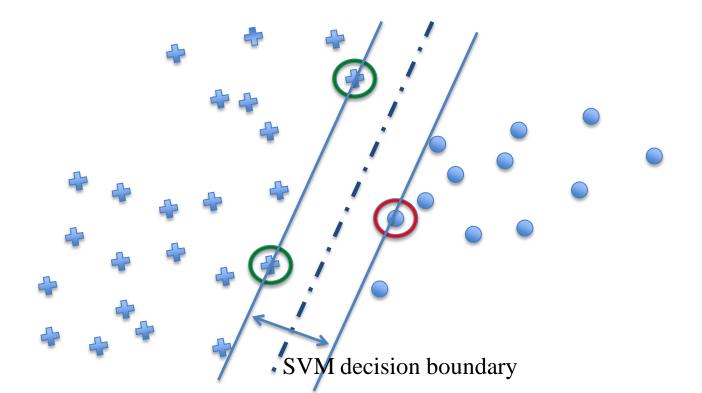
FIRST we <u>need an algorithm</u>
<u>to I.D. a toolmark</u> to a tool

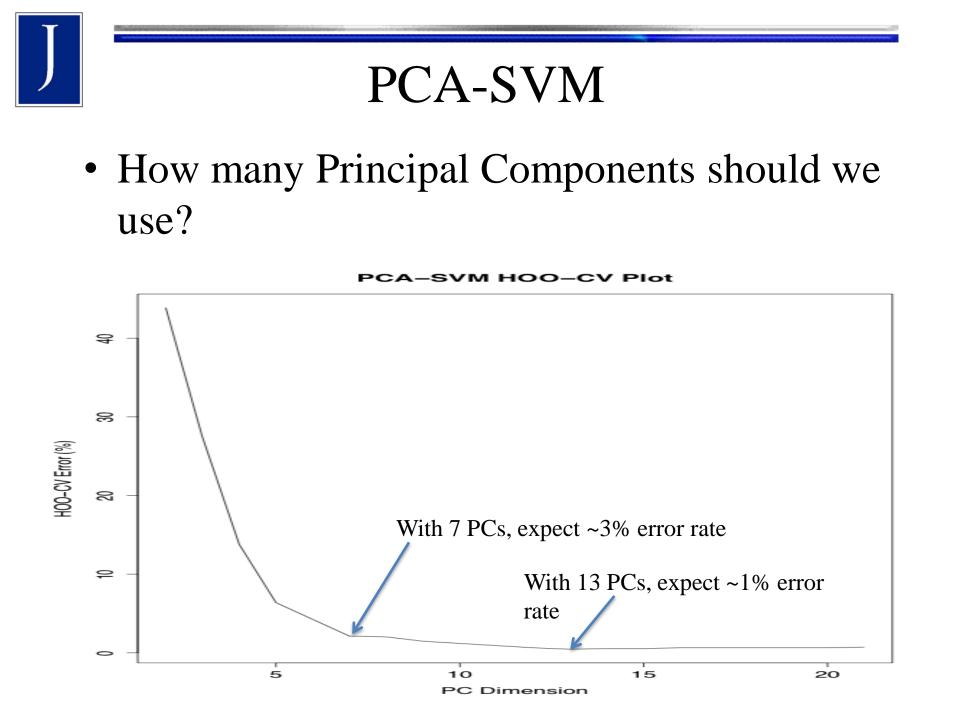
-10

• ~47% variance retained

Support Vector Machines

- Support Vector Machines (SVM) determine efficient association rules
 - In the absence of any knowledge of probability densities



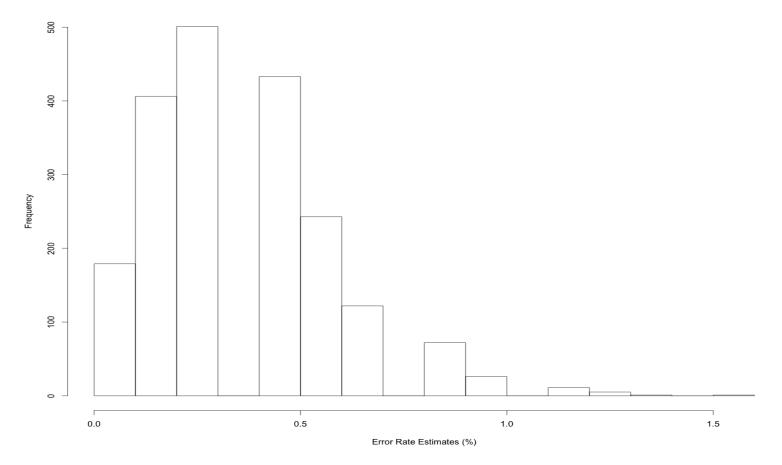


Error Rate Estimation

- **Cross-Validation**: hold-out chunks of data set for testing
 - Known since 1940s
 - Most common: Hold-one-out
- **Bootstrap**: Randomly selection of observed data (with replacement)
 - Known since the 1970s
 - Can yield <u>confidence intervals around error rate</u> <u>estimate</u>
- The Best: Small training set, BIG test set

18D PCA-SVM Primer Shear I.D. Model, 2000 Bootstrap Resamples

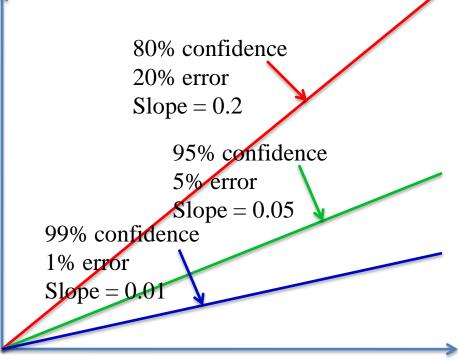
Bootstraped Error Rates for SVM Classification



Refined bootstrapped I.D. error rate for primer shear striation patterns= 0.35%95% C.I. = [0%, 0.83%] (sample size = 720 real and simulated profiles)

How good of a "match" is it? **Conformal Prediction**

- Can give a judge or jury an easy to understand measure of reliability of classification result
 - Confidence on a scale of 0%-100%
- of Ej • This is an orthodox "frequentist" approach Jumulative #
- Developed from principals known since the 1930s



Sequence of Unk Obs Vects

Empirical Bayes'

- Computer outputs a "match"
 - What's the **probability it is truly not a** "match"?

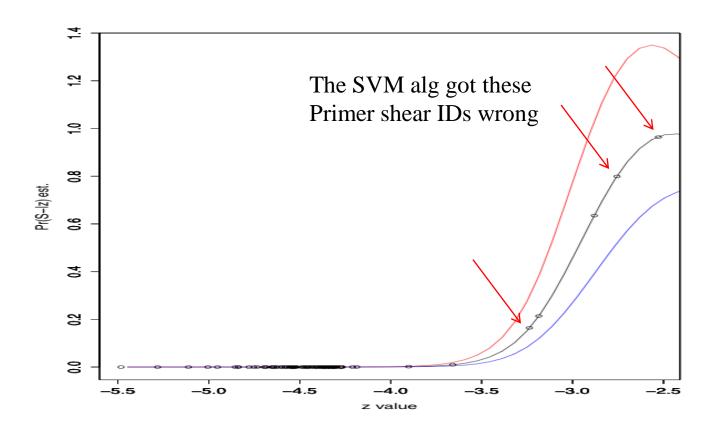
Get it from Bayes' Rule:

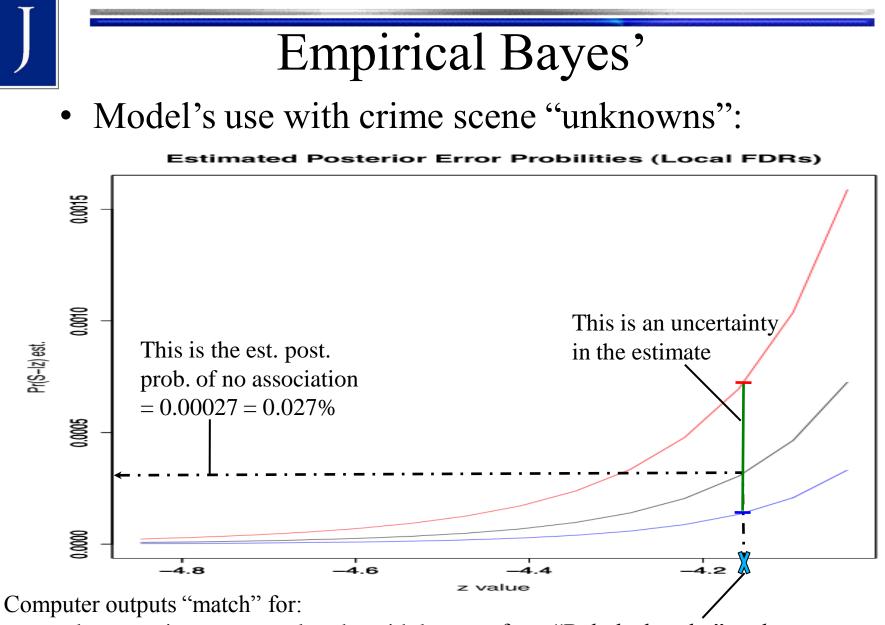
Probability of no actual association
given a test/algorithm indicates a
$$\longrightarrow$$
 $\Pr(S^- | t^+) = \frac{\Pr(t^+ | S^-)}{\Pr(t^+)} \Pr(S^-)$

Name: Posterior error probability (PEP)

Empirical Bayes'

- Use Brad Efron's machinery for "empirical Bayes' twogroups model"
 - Get a calibrated PEP model





unknown crime scene toolmarks-with knowns from "Bob the burglar" tools

Future Directions

- <u>Extend ImageJ</u> surface metrology functionality
- Eliminate alignment step
 - Try invariant feature extraction
- <u>**Parallel</u>** implementation of computationally intensive routines</u>
- <u>Standards board</u> to review statistical methodology/algorithms

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